

SPIE Optical Metrology
“Videometrics, Range Imaging, and Applications XII”
14-15 May 2013, Munich, Germany

On 14-15 May 2013, the 12th SPIE conference “Videometrics, Range Imaging and Applications” was held at the International Conference Centre in Munich, Germany. The event was organized as part of SPIE Optical Metrology conference that included other meetings: Optical Measurement Systems for Industrial Inspection; Modeling Aspects in Optical Metrology; Optics for Arts, Architecture, and Archaeology; Optical Methods for Inspection, Characterization and Imaging of Biomaterials; Automated Visual Inspection). The Videometrics chairs were Fabio Remondino (FBK Trento, Italy) and Mark Shortis (RMIT University Melbourne, Australia). Videometrics was co-organized by ISPRS WGV/1 “Vision Metrology” and its proceedings are available in the SPIE digital libraries as well as hardcopies (Vol. 8781A).

The first Industrial Vision Metrology conference was arranged by Sabry El-Hakim (Carleton Univ., Canada) in 1991 and held at Winnipeg in Canada. Renamed to Videometrics, it was then part of Photonics East at Boston and Philadelphia (1992-1995) before moving to southern California in 1997, first as part of SPIE Photonics West and later in SPIE Electronic Imaging. Since 2011 the Videometrics series is held in Munich as part of SPIE Optical Metrology.

The 2013 Videometrics meeting featured 32 papers - 25 from Europe, 3 from Asia, 2 from USA/Canada and 2 from Australia. The conference was divided into 8 technical sessions, with 29 papers delivered as oral presentations and 3 papers presented in the poster session. The topics of the oral sessions were "Industrial applications and automation", "Automation and image registration", "Point cloud processing and image registration", "Image-based reconstruction, tracking and monitoring", "Active sensors characterization and applications", "TOF cameras calibration and modelling", "3D shape measurement and reconstruction". The conference featured also 2 invited talks: (i) "Fast-robust-accurate: optical measurement systems for industrial applications" by Robert Godding (Aicon 3D Systems GmbH, Germany) and (ii) "Metrological characterization of 3D imaging devices" by Gabriele Guidi (Politecnico of Milano, Italy).

The whole SPIE Optical Metrology 2013 conference, which was held in parallel of a huge exhibition of companies in the fields of metrology, imaging, laser and optics, brought together scientists, engineers, researchers and product developers engaged in optical metrology, industrial measurements, inspections, art conservation and multimedia. The Munich event was an important exchange of ideas and views among the attendees (more than 300 for the Optical Metrology cluster of conferences). The single stream of Videometrics sessions attracted a worldwide interest, with approximately 40-50 participants in the audience for each of the sessions.

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